

20V, 24mΩ, 4A, Single N-Channel

1.Features

- ◆ 20V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±12V

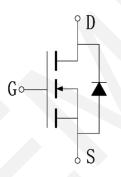
2 An	nlica	tions
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- Power Switching Application
- Load Switching



Pin Description





Schematic Diagram

3.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units	
Drain to Source Voltage	V _{DSS}	20	V	
Gate to Source Voltage	V _{GSS}	±12	V	
Drain Current (DC)	I _D	4	А	
Drain Current (Pulse), PW≤300μs	I _{DP}	16	Α	
Total Dissipation	P _D	0.73	W	
Junction Temperature	Tj	150	°C	
Storage Temperature	T_{stg}	-55 to +150	°C	

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

4.Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	171	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.



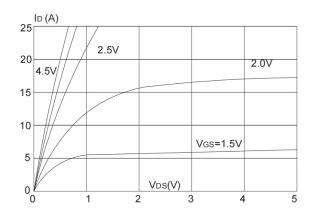
5.Electrical Characteristics at Ta=25°C (Note 3)

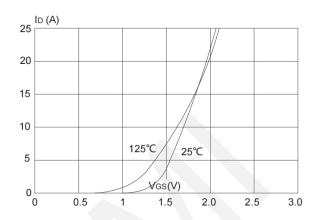
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	20	22		V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20V, V _{GS} = 0V			1	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _{DS} =250μA	0.5	0.7	1	V
Static Drain to Source On-State	Б	$I_D = 4A$, $V_{GS} = 4.5V$		24	27	mΩ
Resistance	R _{DS(on)}	I _D = 2A, V _{GS} = 2.5V		29	35	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,		358		pF
Output Capacitance	C _{oss}	V _{DS} =10V,	\	69.3		pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz		58.5		pF
Turn-ON Delay Time	t _{d(on)}			5		ns
Rise Time	t _r	$V_{DS} = 10V, I_{D} = 4A$		30		ns
Turn-OFF Delay Time	t _{d(off)}	$V_{GS} = 4.5V, R_G = 3\Omega$		48		ns
Fall Time	t _f			36		ns
	Qg	V _{DS} = 10V.		5.6		nC
Total Gate Charge	Q _{gs}	V _{GS} =4.5V,		0.8		nC
	Q _{gd}	I _D = 2A		1		nC
Diode Forward Voltage	V _{FSD}	I _S = 4A, V _{GS} = 0	0.4	0.9	1.4	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

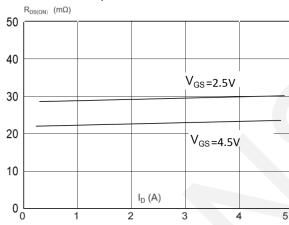


6.Typical Electrical and Thermal Characteristics

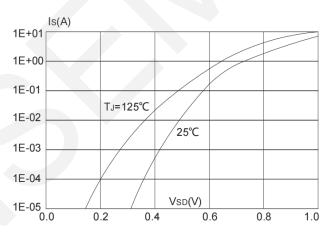




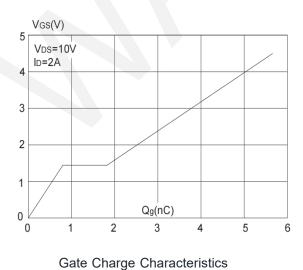
Output Characteristics



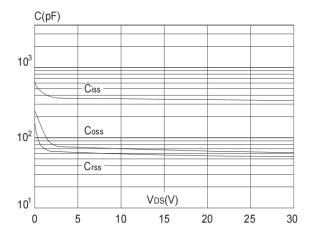
Typical Transfer Characteristics



On-resistance vs. Drain Current

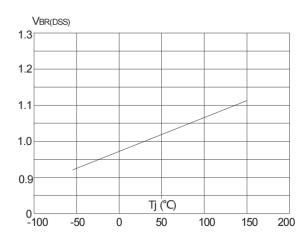


Body Diode Characteristics



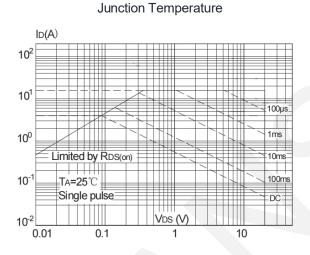
Capacitance Characteristics



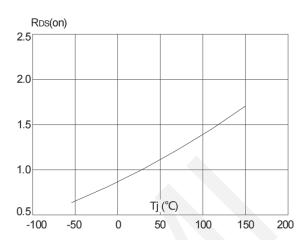


Normalized Breakdown Voltage vs.

malized breakdown voltage vs

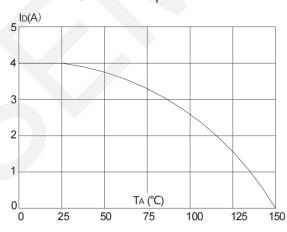


Maximum Safe Operating Area



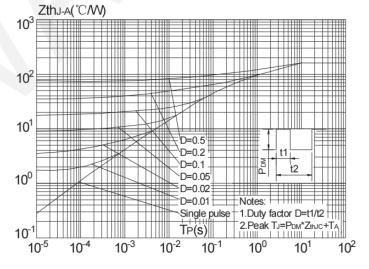
Normalized on Resistance vs.

Junction Temperature



Maximum Continuous Drain Current vs.

Case Temperature

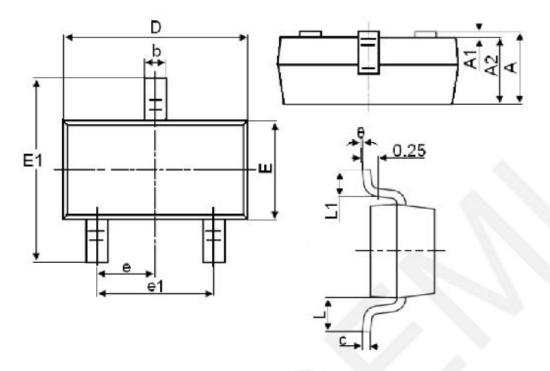


Maximum Effective Transient

Thermal Impedance, Junction-to-Case



7.Package Dimensions



Symbol	Dimensions in Millimeters		
	MIN.	TYP.	MAX.
Α	0.900		1.150
A1	0.000		0.100
A2	0.900		1.050
b	0.300		0.500
С	0.080		0.150
D	2.800		3.000
E	1.200		1.400
E1	2.250		2.550
е		0.950	
e1	1.800		2.000
L		0.550	
L1	0.300		0.500
θ	0°		8°



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